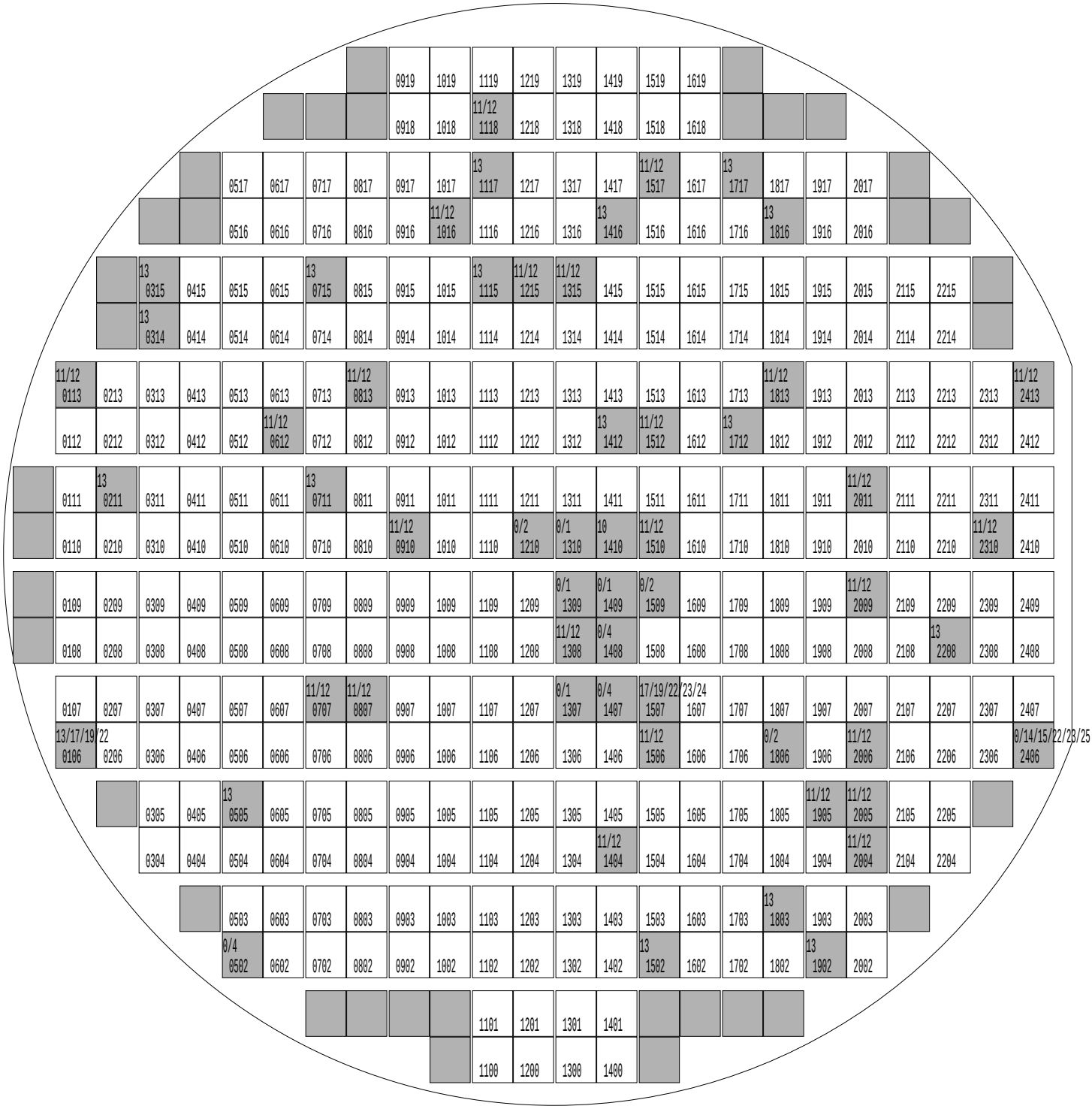
Wafer Map: DXKQN6T



Date probed:	Fri 10 Oct 2003
Chips passed:	304/360
Yield:	84%

Digital failures:	11
Power supply failures:	0
Channel defects (Peds & Cal):	29
Pipeline defects:	18